Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/836,829	TOYA, KEN-ICHI
Examiner	Art Unit
TAN TRINH	2684

SEARCHED					
Class	Subclass	Date	Examiner		
above	UPDATED	7/19/2005	NVO		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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